

IN THE UNITED STATES PATENT AND
TRADEMARK OFFICE

PATENT

Inventor:	Buxton, et al.	Docket No.:	TAI.0800
Serial No.:	10/730,388	Examiner:	Khuu, Cindy D.
Filing Date:	December 07, 2003	Art Unit:	2863
Title:	Methods and Apparatus for Data Analysis		

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner of Patents
P.O. Box 1450
Alexandria, Virginia 22313-1450

Commissioner:

Please be advised that one NPL document, Fountain et al., "Mining IC Test Data to Optimize VLSI Testing," was inadvertently omitted with the submittal of the original Supplemental Information Disclosure Statement filed on December 22, 2006. Although the file was originally submitted with the disclosure, it was rejected by the EFS filing system as being corrupted. It is therefore attached herewith.

In accordance with the duty of disclosure under 37 C.F.R. §1.56 and pursuant to 37 C.F.R. §§1.97-1.98, the reference or references listed and identified on the attached PTO/SB/08-based form are being submitted for consideration by the Examiner.

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This Information Disclosure Statement (IDS) of December 22, 2006 was originally filed under 37 C.F.R. §1.97(e) before the mailing date of any final action under 37 C.F.R. §1.113, a notice of allowance under 37 C.F.R. §1.311, or an action that otherwise closes prosecution of the application. The IDS was accompanied by the fee set forth in 37 C.F.R. §1.17(p). If there are any questions concerning this IDS, the Examiner is requested to contact the undersigned.

Respectfully submitted,

Date: 28 Dec 06

By: 
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